


<b>Search Notes</b> 	<b>Application/Control No.</b> 10531629	<b>Applicant(s)/Patent Under Reexamination</b> LOCCUFIER ET AL.
	<b>Examiner</b> Eoff, Anca	<b>Art Unit</b> 1795

SEARCHED			
Class	Subclass	Date	Examiner
430	270.1, 300, 302, 303	9/23/2008	AE
522	166	9/23/2008	AE
528	423	9/23/2008	AE

SEARCH NOTES			
Search Notes		Date	Examiner
Text search in East (search history attached)		9/23/2008	AE
Consulted with Primary Examiners John Chu, Sin Lee and SPE David Wu		9/23/2008	AE

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
430	270.1, 300, 302, 303	9/23/2008	AE
522	166	9/23/2008	AE
528	423	9/23/2008	AE

/A. E./  
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